

Table of Contents

Preface

Structure Determination from Very Small Crystals M.M. Harding	3
Analysis of Strain Fields by Means of Diffraction-Line Broadening J.G.M. Van Berkum, R. Delhez, T.H. de Keijser and E.J. Mittemeijer	11
Application of the Smooth Genetic Algorithm for Indexing Powder Patterns – Tests for the Orthorhombic System W. Paszkowicz	19
A Criterion for Correct Indexing of Powder Diffraction Diagrams Based on Preferred Orientation (Texture) H.J. Bunge and N.J. Park	25
Rietveld Refinement Using Debye-Scherrer Film Techniques L. Lutterotti, A.F. Gualtieri and S. Aldrichetti	29
Integration of Intensity and Angle Calibration into Rietveld Refinement J. Schneider and A. Kern	35
Ab Initio Calculations of Diffraction Patterns of Submicron Powders H. Marciniak, S. Gierlotka and B.F. Palosz	39
Addition Method in the Quantitative Analysis: Dependence of Error on the Quantity of Additive T. Balic Zunic	43
DOP-FIT Method for Quantitative Analysis of Multicomponent Powders B. Gržeta, S. Popović and H. Toraya	49
Quantitative X-Ray Phase Analysis of Materials with Disordered Structures R.P. Purlys, S.E. Stasiūnas and J.A. Yakimavichius	55
A New Possibility for Powder Diffraction: The Characterization of the Domain Microstructure in a Ferroelectric Material C. Valot, N. Floquet, M.T. Mesnier and J.C. Niepce	59
X-Ray and Neutron Analysis of the Dislocation Content in Plastically Deformed β-Brass D. Breuer and P. Klimanek	67
The Cross Correlation Method: A Useful Tool for Peak Shift Determination in XSE V.R. Vosberg, W. Fischer and W.J. Quadackers	73
Empirical Texture Correction for Different Diffraction Geometries: Experimental Tests R. Cerný and V. Valvoda	77
New Opportunities in the Texture and Stress Field by the Whole Pattern Analysis M. Ferrari, L. Lutterotti, S. Matthies, P. Polonioli and H.R. Wenk	83
Analysis of Peak Shapes in X-Ray Diffractometry (GUINIER Geometry) of Standard Materials Using Asymmetric Profile Functions A.M. Schneider, W. Paszkowicz, P. Behrens and J. Felsche	89
Diffraction Anomalous Fine Structure Analysis on $(\text{Bi,Pb})_2\text{PtO}_4$ Powders J. Vacinova, J.-. Hodeau, P. Bordet, M. Anne, D.E. Cox, A. Finch, P. Pattison, W. Schweggle, H. Graafsma and Å. Kvick	95
Rapid Polymer Identification with X-Ray Diffraction S. Haaga, W. Engel, M. Tietz and H.-. Radusch	101
An Improved X-Ray Image Plate Detector for Diffractometry M. Thoms, H. Burzlaff, A. Kinne, J. Lange, H. von Seggern, R. Spengler and A. Winnacker	107
Refinement of Powder Diffraction Data Collected Using Imaging Plates D.J. Cookson, G.J. Foran, B.A. Hunter, Ismunandar and B.J. Kennedy	113
X-Ray Imaging Using Fluorescence or Polycrystalline Diffraction T. Wroblewski	119
Stress Analysis Using an Area Detector A. Schubert, B. Michel and B. Kämpfe	125
A Fully Automated High-Temperature Powder Diffractometer A. Kern and W. Eysel	131

A New High-Temperature Camera B. Koppelhuber-Bitschnau, F.A. Mautner, P. Worsch and J. Gautsch	137
A Low-Temperature Option Down to -70° C for a High-Temperature Attachment B. Baumgartner	143
In-Situ Time Resolved Synchrotron Powder Diffraction Studies of Syntheses and Chemical Reactions P. Norby	147
Assessment of an In-Situ Reactor Cell: Temperature Calibration and Reliability of Diffracted Intensity M. Bellotto and B. Rebours	153
Profile Smoothing and Differentiation with Reciprocal Polynomials L.A. Solovyov	161
How to Solve the Problems for the Indexation of Complex Materials Using Laboratory Powder Diffraction: Application to Metal Phosphonates A. Cabeza, M.Á.G. Aranda, M. Martínez-Lara and S. Bruque	165
Application of the Rietveld Method to XRD Patterns of Thin Films Recorded in Parallel Beam Geometry W. Pitschke	171
Application of a New Rietveld Software for Quantitative Phase Analysis and Lattice Parameter Determination of AlN-SiC-Ceramics T. Taut, J. Bergmann, G. Schreiber, A. Börner and E. Müller	177
An Interactive Windows Program for Profile Fitting and Size/Strain Analysis S. Krumm	183
Strain Scanning Using X-Rays and Neutrons P.J. Webster	191
Resonant Powder X-Ray Diffraction J.P. Attfield	201
The Breadth and Shape of Instrumental Line Profiles for the Powder Diffraction Station 2.3 at the Daresbury Laboratory SRS P. Scardi, M. Leoni, G. Cappuccio, J.I. Langford and R.J. Cernik	207
A New White Beam Powder Diffraction Facility at the Daresbury Laboratory Synchrotron Radiation Source S.M. Clark, R.J. Cernik, A. Grant, S. York, P.A. Atkinson, A. Gallagher, D.G. Stokes, S.R. Gregory, N. Harris, W. Smith, M.H. Hancock, M.C. Miller, K. Ackroyd, R. Farrow, R. Frances and D. O'Hare	213
The High Resolution Powder Diffraction Beam Line at ESRF A. Fitch	219
D2AM: A CRG Beamline at ESRF for Material Science Studies J.F. Béjar, J.P. Simon, J.-. Ferrer and D. Dallé	223
Through-Thickness Strain Scanning Using Synchrotron Radiation P.J. Webster, X.D. Wang and G. Mills	227
Structure Refinement with Synchrotron Data: R-Factors, Errors and Significance Tests D.E. Cox and R.J. Papoular	233
A Dynamic Study of the Formation of Gas Clathrate Hydrates: In-Situ Synchrotron X-Ray Diffraction and Differential Scanning Calorimetry C.A. Koh, J.L. Savidge, C.C. Tang, R.E. Motie, X.P. Wu, R.I. Nooney and R. Westacott	239
Neutron Powder Diffractometer at the Budapest Research Reactor E. Sváb, G. Mészáros and F. Deák	247
ROT/DIFF: A Versatile Neutron Powder Time-of-Flight Diffractometer of Wide d-Spacing Coverage W. Schäfer, W.A. Kockelmann, E. Jansen, W. Schmidt, H. Tietze-Jaensch and G. Will	253
Neutron Diffraction Pole-Figure Measurements Using a Pulsed White Beam and the Linear Julios-Detector E. Jansen, W. Schäfer, G. Will and K.S. Knight	259
Equipment for Residual Stress Measurements with the High Resolution Fourier Diffractometer: Present Status and Prospects A.M. Balagurov, G.D. Bokuchava, J. Schreiber and Y.V. Taran	265
High-Resolution Neutron Powder Diffractometry on Samples of Small Dimensions P. Mikula, J. Šaroun, M. Vrána, P. Lukáš and V. Wagner	269

High-T_c Superconductor Studies by Means of High-Resolution and High-Intensity Neutron Powder Diffraction at the IBR-2 Pulsed Reactor	
A.M. Balagurov	275
Magnetic Structures in Cubic Laves Phase	
R. Plumier	281
Applications of a Thin Film Diffractometer	
P. Van der Sluis	289
Structure Parameter Determination of Thin Films by Intensity Fitting in GIABD-Geometry	
J. Klimke and H. Wulff	295
Analysis of Residual Stress Gradients in Thin Films Using SEEMANN-BOHLIN-X-Ray Diffraction	
K. Fischer and H. Oettel	301
The Crystal Structure and Texture Analyses of Polycrystalline Thin Film Sample Using Multiple Diffraction Datasets Obtained by Asymmetric Diffraction Technique	
H. Toraya	307
An Analysis of the Influence of Crystallographic Texture on Residual Stress Estimation for Metallic Films and Coatings	
I. Iordanova, D. Neov, K.S. Forcey, H. Heitzek and R. Bezdushnyi	311
Residual Stress in Ti(C,N) Coatings on HSS Substrate	
F. Arrando, J. Bassas, X. Alcobé and J. Esteve	317
Dynamic Studies from Laboratory X-Rays	
P. Bénard, J.-. Auffrédic and D. Louër	325
The Thermal Decomposition of $\text{CeM}'_2(\text{NO}_3)_6$ ($\text{M}' = \text{K}, \text{NH}_4, \text{Rb}$) Studied by Temperature-Dependent X-Ray Powder Diffraction	
N. Guillou, N. Audebrand, M. Louër, J.-. Auffrédic and D. Louër	335
X-Ray Characterization of Complex Oxide Catalysts under Preparation and Reaction Conditions: Catalysts for Methanol Synthesis	
L.M. Plyasova	341
Hydrotalcite Thermal Decomposition Mechanism: In Situ Study by XRD, AWAXS and EXAFS of a Layered Catalyst Precursor	
M. Bellotto, D. Bazin, M. Bessière, O. Clause, E. Elkaim, J. Lynch and B. Rebours	347
Time- and Temperature Resolved X-Ray Powder Diffraction: In Situ Observation of the Ammonolysis Reaction of NH_4TaF_6	
W. Weber and E. Schweda	353
Temperature Resolved X-Ray Diffraction of Ammonium Nitrate Evaluated with Rietveld Analysis	
M. Herrmann and W. Engel	359
Dynamic Observation of Crystallographic and Micro Structural Changes Associated with the Collapse and Recrystallisation of Cd Exchanged Zeolite-A	
L.M. Colyer, G.N. Greaves, B.U. Komanschek, M.A. Roberts, A.J. Dent, K.K. Fox and S.W. Carr	363
The Dehydration Process in the Natural Zeolite Laumontite: A Real-Time Synchrotron X-Ray Powder Diffraction Study	
G. Artioli, K. Ståhl and J.C. Hanson	369
A Kinetic of the B1-B2 Phase Transition of Rubidium Iodide as a Function of Pressure	
A.R. Rezai-Fard, J. Anwar and S.M. Clark	375
High-Pressure Behaviour of Titanium Dioxide	
L. Gerward and J.S. Olsen	383
GIXD (Grazing Incidence X-Ray Diffraction) as a Tool for the In Situ Investigation of Electrochemical Reactions of Metals in Electrolyte Solutions: The Lead Electrode in 5 M Sulphuric Acid	
G.E. Nauer	387
Magnetostriction Studied with Precise High Temperature Powder Diffraction	
L. Petrás, A. Preisinger and K. Mereiter	393
High Temperature X-Ray Diffraction Studies on the Crystallization of Amorphous Fe-Zr-B Alloys	
N. Mattern, A. Danzig, S. Doyle and M. Müller	399
Real Time SAXS/WAXS/DTA Measurements of the Crystalline/Amorphous Transition of Low Molecular Weight Hydrogenated Polybutadiene	
R. Haswell, J.B. Van Mechelen, C.T.J. Mensch and H. De Groot	405

Crystallization of Gel-Processed PZT Powders J.C. Fernandes, D.A. Hall and G.N. Greaves	411
Kinetics of the Formation of PLZT: An In-Situ XRD Study M.A. Roberts, G. Sankar, C.R.A. Catlow, J.M. Thomas, G.N. Greaves and R.H. Jones	417
A General Method for the Analysis of Non-Isothermal Kinetic Data J.A. Kennedy and S.M. Clark	423
European Standardization of XRPD Measurements G. Berti	431
Powder Diffraction Simulation in the CAD of Multicomponent Systems V.P. Vorobjeva and V.I. Lutsyk	437
The Effect of Impurities on X-Ray Compton Scattering in Belite R.P. Purlys, S.E. Stasiūnas and J.A. Yakimavichius	439
Study of the Growth of Thin Epitaxial CVD Diamond Films on Silicon S. Geier, R. Hessmer, M. Schreck, B. Stritzker, B. Rauschenbach, K. Helming, K. Kunze and W. Erfurth	445
Residual Stress in Diamond Coatings by Synchrotron Radiation XRD P. Scardi, M. Leoni, V. Sessa, M.L. Terranova and G. Cappuccio	451
Grain Size Analysis in Electrodeposited Cu-Coatings S. Schläfer, P. Klimanek, I. Handreg, G. Heinzel and G. Lanza	457
On the Thickness-Dependence of Textures in Electrodeposited Copper-Coatings I. Handreg, P. Klimanek, G. Lanza and M. Schneider	463
Variation of Preferred Orientation of Erbium Thin Films with Temperature and Substrate G.R.G. Craib, M.A. Player, M.J. Rodman and C.C. Tang	469
Microstructure Formation in Electrodeposition of Highly Supersaturated Cu-Pb and Ag-Pb Layers T. Barthel, P. Klimanek, C.J. Raub and A. Zielonka	475
Residual Stress in Plasma-Sprayed Ceramic Coatings W. Fischer, H. Gruhn and W. Malléner	481
X-Ray Diffraction Microstructural Characterization of PZT ($\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$) and Pt Thin Films on TiN/Ti/BPSG/Si Structures F. Varnière, B. Ea Kim, R. Bisaro and G. Chevrier	487
Characterization of a New Phase in WO_3 Thin Films Grown by Sol-Gel Method L. Sangaletti, L.E. Depero and L. Armelao	493
Structure Analysis of Annealed Polycrystalline Ag/NiFe Multilayers M. Chládek, C. Dorner, M. Matner and V. Valvoda	499
X-Ray Reflectivity and Diffuse Scattering Study of Thermally Treated $\text{W}_{1-x}\text{Si}_x/\text{Si}$ Multilayers M. Jergel, E. Majková, V. Holý, R. Senderák and S. Luby	505
Characterization of Ni/C Multilayers with Fluorescence XAFS Experiments at Fixed Standing Wave Field Positions D.C. Meyer, T. Holz, R. Krawietz, K. Richter, B. Wehner and P. Paufler	511
X-Ray Diffraction Studies of Silica: Titania Sol-Gel Glasses J.S. Rigden, R.J. Newport, M.E. Smith and P.J. Dirken	519
Shallow Angle X-Ray Diffraction from In-Situ Silica: Titania Sol-Gel Thin Films J.S. Rigden, R.J. Newport, M.E. Smith and P.J. Dirken	525
X-Ray Powder Diffraction Investigation of the Metastable Phase $\text{Sr}_2\text{Ti}_5\text{O}_{12}$ Occurring in Hi-Tech Glass Ceramics B. Peplinski, T. Hübert, M. Willfahrt and U. Banach	531
Evidence for the Compensated Continuous Random Network Model for Spodumene Glass and Analogues M.C. Jermy, G.N. Greaves, M.E. Smith, G. Bushnell-Wye, A.C. Hannon, R.L. McGreevy, G. Derst and B. Tilley	537
Structural Studies of Semiconductor-to-Metal Transition in the Bulk Amorphous Solid Solutions $(\text{GaSb})_{1-x}(\text{Ge}_2)_x$ under High Pressure A.V. Sapelkin, S.C. Bayliss, A.G. Lyapin, V.V. Brazhkin, S.M. Clark, A.J. Dent, J.P. Itié and A. Polian	543
Diffraction Methods for the Characterisation of Defects in Intermetallic Compounds L. Lutterotti, S. Gialanella and R. Caudron	551

Investigation of Structure and Substructure of a Martensitic Stainless Steel I. Iordanova, R. Bezduzhnyi, K.S. Forcey, R. Damianova and V. Bojinov	557
Influence of Laser Treatment on Martensitic Transformation Characteristics in Fe-Ni Alloys V.E. Danil'chenko and Y.M. Sidorin	563
Influence of Multiple Martensitic Transitions on the Crystal Structure of Austenite Single Crystals V. Bondar and V.E. Danil'chenko	567
Independent Determination of the Temperature Factor of a Ga Atom in a GaAs Powder Sample R. Uno, H. Ozawa and K. Ohsumi	571
Improved X-Ray Powder Diffraction Data for the Disordered η-Cu₆Sn₅ Alloy Phase B. Peplinski, G. Schulz, D. Schultze and E. Schierhorn	577
Once More about Monoclinic Al₁₃Co₄ C. Freiburg, B. Grushko, R. Wittenberg and W. Reichert	583
The Magnetic Structures of YMn₂Si₂ and LaMn₂Si₂ M. Hofmann, S.J. Campbell, X.L. Zhao, Y. Nakayama and R. Cywinski	587
Structural Refinement and Stability of Silicon XII E.J. MacLean, P.D. Hatton, J. Crain, R.O. Piltz, S.J. Clark and R.J. Cernik	595
Structural Determination of (CH₃)₂SBr₂ Using the Swiss-Norwegian Beam Line at ESRF A.J. Mora, A. Fitch, P.N. Gates and A. Finch	601
Mechanochemical Transformation of Haematite to Magnetite: Structural Investigation M. Hofmann, S.J. Campbell and W.A. Kaczmarek	607
Investigations on Stability and Long-Term Behaviour of AFm Phases at Higher Temperatures by X-Ray Powder Diffraction Methods F. Goetz-Neunhoffer and H. Pöllmann	615
Dynamic Studies on the Reactions of Calcium Aluminate Cements with Sulphate Solutions Monitored by Synchrotron Radiation Energy-Dispersive Diffraction S. Rashid, X. Turrillas and P. Barnes	621
The Structure of Copper Chromite Activated by Hydrogen T.A. Krieger, L.M. Plyasova, L.P. Solovyeva, T.M. Yur'eva and O.V. Makarova	627
Structural Phase Transitions in KTaO₃:Li Crystals: Evidence from X-Ray Powder Diffraction Data S.A. Ivanov, V.V. Zhurov, G. Hermeler and W. Depmeier	633
X-Ray Studies of Products Formed during Air-Calcination of Contaminated Zinc Carbonates J. Maixner, J. Jandová, H. Hejdová and J. Selucká	639
The New Intermediate Phase Detected during the In Situ Investigation of Sodium Adipate into LiCl*2Al(OH)₃*nH₂O V.P. Isupov, B.P. Tolochko and A.V. Besserguenev	645
Phase Formation in PZN-BT-PT Ceramics M.J. McGarry and D.A. Hall	651
Phase Homogeneity in Nd-Doped Lead Titanate Ceramics M.R. Cockburn and D.A. Hall	657
Study of Polytype Phase Transition β to α SiC by Qualitative and Quantitative Analysis of Stacking Disorder by X-Ray Diffraction and Structure Modelling S. Stelmakh, B.F. Palosz and S. Gierlotka	663
NaA-Zeolites Modified by Me²⁺-Cations U. Steinike, K. Jancke, W. Lutz, E. Schreier and G. Walther	669
Structure of Metal Hydrides from X-Ray, Synchrotron and Neutron Powder Diffraction R. Cerný	677
Structure Refinements of Alkali Fullerides T. Pusztai, G. Bortel, G. Faigel, G. Oszlányi, M. Tegze, P.W. Stephens and L. Forró	683
Rietveld Refinement for Selected Pseudobinary Semiconductors W. Paszkowicz, Z. Golacki, Z. Spolnik, Z.R. Żytkiewicz, F. Firszt, H. Meczynska and W. Giritat	689
Comparative Structure Refinement of MO₃.1/3H₂O (M = Mo, W) from X-Ray and Neutron Powder Diffraction Data and Dehydration Process L. Seguin, B. Gérard, G. Chevrier and M. Touboul	695

The Crystal Structures of Li⁺ Conducting Phases Li_{0.5-3x} RE_{0.5+x} TiO₃: RE=Pr,Nd, x≈0.05, from Powder Neutron Diffraction Data	
R.I. Smith, J.M.S. Skakle, G.C. Mather, M. Morales and A.R. West	701
Structure Transformation in Diamine-Dichloro-Palladium (II) Studied by X-Ray Powder Diffraction	
L.A. Solovyov, S.D. Kirik, I.S. Yakimov, M.L. Blokhina and A.I. Blokhin	705
Neutron Diffraction Studies of Me₂UX₆ Ionic Conductors	
K. Maletka, E. Ressouche, W. Szczepaniak, L. Rycerz and A. Murasik	711
Rietveld Refinement of Cobalt and Cobalt-Zinc Substituted AIPO-11 Aluminophosphates	
A. Meden, N. Novak Tušar and V. Kaucic	717
Copper(II)-Hydroxo-Oxoruthenate(VI): CuRuO₂(OH)₄ – Ab Initio Structure Determination by X-Ray Powder Diffraction –	
T.W. Hansen	723
Barium-Oxomercurato(II)-Oxoruthenate(VI) BaHgRuO₅: A New Oxomercurate with a Cyclic Mercurate-Ruthenate Anion High Pressure Synthesis and Ab Initio Structure Approach by X-Ray Powder Diffraction	
T.W. Hansen, A. Le Bail and Y. Laligant	729
Structural Characterization by Neutron Diffraction of FeRGe₂O₇, R = La, Pr	
L. Bucio, C. Cascales, J.A. Alonso and I. Rasines	735
Crystal Structure of LiB₅O₈·5H₂O	
M. Touboul, E. Bétourné and L. Seguin	741
Resolution of the Crystal Structure of the Deficient Perovskite LaNiO_{2.5} from Neutron Powder Diffraction Data	
J.A. Alonso and M.J. Martínez-Lope	747
Structural Trends in Pyrochlore Oxides	
B.J. Kennedy	753
High-Resolution X-Ray Powder Diffraction Studies of Some Mg- and Si- Substituted Brownmillerites	
A.C. Lewis, J.K. Cockroft, P. Barnes, C. Hall, R.J. Cernik, C.C. Tang and H. Pöllmann	759
Rietveld Studies of Leucite Analogues	
A.M.T. Bell, C.M.B. Henderson and R.J. Cernik	765
High Resolution Neutron Diffraction Study of Structural Anomalies in K_{1-x}(ND₄)_xD₂PO₄ Mixed Crystals	
A.V. Belushkin, R.M. Ibberson and L.A. Shuvalov	771
Characteristics of the Monoclinic-Tetragonal Transition and the Order-Disorder Transition in Barium Hollandites	
R.W. Cheary, R. Thompson and P. Watson	777
Crystal Structure Refinement of the Mechanically Activated Spinel-Ferrite	
V. Šepelák, K. Tkáčová, V.V. Boldyrev and U. Steinike	783
Structural Analysis of Polycrystalline CaRuO₃ and SrRuO₃ Ceramics from Room Temperature Up to 1273 K	
S.L. Cuffini, J.A. Guevara and Y.P. Mascarenhas	789
New Rare Earth Palladates Ln₂Pd₂O₅	
R.B. Dötzer and W. Eysel	795
Rietveld Refinement of the Crystal Structure of Silver-Oxalate from Neutron Powder Diffraction Data	
L. Eriksson	801
Quantification of a Mixture of Synthetic Alite and Belite by the Rietveld Method	
J. Neubauer and R. Sieber	807
Structure and Dynamics of Organic Molecules in a Sodalite Matrix: A Combined Molecular Modeling and RIETVELD Refinement Approach	
A.M. Schneider and P. Behrens	813
Crystal Structure Refinement of Ba₅Nb₄O₁₅ and Ba₅Nb₄O_{15-x} by Rietveld Analysis of Neutron and X-Ray Diffraction Data	
S. Pagola, G. Polla, G. Leyva, M.T. Casais, J.A. Alonso, I. Rasines and R.E. Carbonio	819
Crystal Structure and Morphology of Disordered AlNbO₄ from X-Ray Powder Diffraction	
O. Greis, R. Ziel, D.E. García, N. Claussen, B. Breidenstein and A. Haase	825

A Combined Powder X-Ray/Neutron Diffraction Study of Cation Distributions in the Ternary Sulphide VCr_2S_4 A.V. Powell and D.C. Colgan	831
Microstructure of Magnetite from XRPD Data in Relation to Magnetism G. Berti and E. Pinna	839
Residual Stress of Monoclinic Zircon Obtained by X-Ray Diffraction in ZY4 Oxidized Cladding Tubes T. Jacquot, R. Guillén, M. François, B. Bourniquel and J. Senevat	845
X-Ray Strain Analysis of Quenched and Ground Alumina Samples N. Ganey, G. Gosmanová and I. Kraus	851
CsMnF_4 under Hydrostatic Pressure: Structural Phase Transitions and Influence of the Pressure Calibrant F. Palacio, M.C. Moron, G. Antorrena, S. Clark and A. Devine	855
Low Temperature Crystal Structures of Globular Organic Molecules A.J. Mora and A. Fitch	863
Powder Diffraction Investigations on Molecular Crystals of the Ring System Cyclo-Tri (2,6-Pyridyl Formamidine) J. Bergmann, D. Jehnichen, J. Tobisch, P. Friedel, M. Rillich and T. Taut	869
An X-Ray Study of N-(2,3-Dihydroxybenzylidene) 3,4,5-Trimethoxyaniline and its Hydrochloride Derivative J. Estienne, C. Kodjo, J. Tenon and O. Cerclier	873
Comparison of Powder and Single Crystal Data of $\text{C}_{60}(\text{C}_{14}\text{H}_{10}\text{O}_2)$, an Oxygen Containing Anthracene Derivative of C_{60} G. Bortel, G. Oszlányi, G. Faigel, M. Tegze, T. Pusztai and S. Pekker	879
Scattering of X-Rays by Aryl Ketones R.J. Rakauskas, R. Purlys and S. Stasiūnas	885
Poly (Vinyl Butyral) Crystallinity A. Duta, R. Tica, D. Perniu and B. Cismas	889
Magnetic Properties of $\text{Yb}_2\text{Cu}_2\text{O}_5$ by Powder Neutron Diffraction A. Murasik, P. Fischer, H. Rundlöf, R. Tellgren and R. Troc	895
Texture Analysis of the YBCO Thin Films Reveals Twinning in the YBCO Crystallites D. Machajdik, K. Fröhlich, F. Weiss and A.P. Kobzev	901
Bi(2212) Films Prepared by Liquid Phase Epitaxy: Structure Aspects T.D. Aksenova, P.V. Bratukhin, B.L. Krivts and S.V. Shavkin	907